nexperia

## Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023
Based on structural similarity

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115 V .

Calculation of FIT and MTTF
Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test \# 5)
Confidence level $60 \%$, derated to $55^{\circ} \mathrm{C}$, activation energy 0.7 eV , test time 168 to 1000 hours

| Wafer Fab | Technology | Quantity | Rejects | Failure Rate (FIT) |
| :--- | :--- | :--- | :--- | :--- |
| Nexperia    <br> DHAM Protection Std Bipolar 760 0 | MTTF (hrs) |  |  |  |

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